

FDD2670

200V N-Channel PowerTrench® MOSFET

General Description

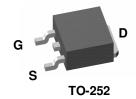
This N-Channel MOSFET has been designed specifically to improve the overall efficiency of DC/DC converters using either synchronous or conventional switching PWM controllers.

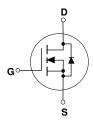
These MOSFETs feature faster switching and lower gate charge than other MOSFETs with comparable ${\rm RDS}_{({\rm ON})}$ specifications.

The result is a MOSFET that is easy and safer to drive (even at very high frequencies), and DC/DC power supply designs with higher overall efficiency.

Features

- 3.6 A, 200 V. $R_{DS(ON)} = 130 \text{ m}\Omega$ @ $V_{GS} = 10 \text{ V}$
- Low gate charge
- · Fast switching speed
- High performance trench technology for extremely low $R_{\mbox{\scriptsize DS(ON)}}$
- · High power and current handling capability





Absolute Maximum Ratings T_A=25°C unless otherwise noted

Symbol	Parameter		Ratings	Units
V _{DSS}	Drain-Source Voltage		200	V
V_{GSS}	Gate-Source Voltage		±20	V
I _D	Drain Current - Continuous	(Note 1)	3.6	Α
	Drain Current - Pulsed		20	
P _D	Maximum Power Dissipation @ T _C = 25°C	(Note 1)	70	W
	@ T _A = 25°C	(Note 1a)	3.2	
	@ T _A = 25°C	(Note 1b)	1.3	
dv/dt	Peak Diode Recovery dv/dt	(Note 3)	3.2	V/ns
T _J , T _{STG}	Operating and Storage Junction Temperature Range		-55 to +150	°C

Thermal Characteristics

R _{eJC}	Thermal Resistance, Junction-to-Case	(Note 1)	1.8	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	(Note 1b)	96	°C/W

Package Marking and Ordering Information

Device Marking Device		Reel Size	Tape width	Quantity	
FDD2670	FDD2670	13"	16mm	2500 units	

Symbol	Parameter	Test C	onditions	Min	Тур	Max	Units
Drain-Sc	ource Avalanche Ratings (Note	1)			I	I	
W _{DSS}	Single Pulse Drain-Source Avalanche Energy	$V_{DD} = 100 \text{ V},$	$I_D = 3.6 \text{ A}$			375	mJ
I _{AR}	Maximum Drain-Source Avalanche Current					3.6	Α
Off Char	acteristics	_					
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D =$: 250 μA	200			V
$\frac{\Delta BV_{DSS}}{\Delta T_J}$	Breakdown Voltage Temperature Coefficient		eferenced to 25°C		214		mV/°C
I _{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = 160 \text{ V},$	$V_{GS} = 0 V$			1	μΑ
I _{GSSF}	Gate-Body Leakage, Forward	$V_{GS} = 20 \text{ V},$	$V_{DS} = 0 V$			100	NA
I _{GSSR}	Gate-Body Leakage, Reverse	$V_{GS} = -20 \text{ V},$	$V_{DS} = 0 V$			-100	NA
On Char	acteristics (Note 2)						
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_D =$: 250 μA	2	4	4.5	V
$\Delta V_{GS(th)} \over \Delta T_J$	Gate Threshold Voltage Temperature Coefficient	$I_D = 250 \mu\text{A}, \text{R}$	eferenced to 25°C		-10		mV/°C
R _{DS(on)}	Static Drain–Source On–Resistance	$V_{GS} = 10 \text{ V},$ $V_{GS} = 10 \text{ V}, I_D$	$I_D = 3.6 \text{ A}$ = 3.6 A T _J = 125°C		100 205	130 275	mΩ
I _{D(on)}	On-State Drain Current	$V_{GS} = 10 \text{ V},$		20			Α
g FS	Forward Transconductance	$V_{DS} = 5 V$,	$I_D = 3.6 A$		15		S
Dynamic	Characteristics						
C _{iss}	Input Capacitance	$V_{DS} = 100 \text{ V}, \qquad V_{GS} = 0 \text{ V},$			1228		PF
Coss	Output Capacitance	f = 1.0 MHz			112		PF
C _{rss}	Reverse Transfer Capacitance				17		pF
Switchin	g Characteristics (Note 2)						
t _{d(on)}	Turn-On Delay Time	$V_{DD} = 100 \text{ V},$	$I_D = 1 A$		13	23	ns
t _r	Turn-On Rise Time	V _{GS} = 10 V,	$R_{GEN} = 6 \Omega$		8	16	ns
$t_{\text{d(off)}}$	Turn-Off Delay Time	1			30	48	ns
t _f	Turn-Off Fall Time	1			25	40	ns
Qg	Total Gate Charge	V _{DS} = 100 V,	I _D = 3.6 A,		27	43	nC
Q _{gs}	Gate-Source Charge	V _{GS} = 10 V			7		nC
Q_{gd}	Gate-Drain Charge				10		nC
Drain-Se	ource Diode Characteristics	and Maximu	m Ratings				
Is	Maximum Continuous Drain-Source					2.1	Α
V _{SD}	Drain-Source Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_{S}$	s = 2.1 A (Note 2)		0.7	1.2	V

Notes

1. R_{BJA} is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. R_{BJC} is guaranteed by design while R_{BCA} is determined by the user's board design.

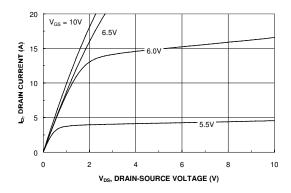


Scale 1 : 1 on letter size paper

2. Pulse Test: Pulse Width < 300 μ s, Duty Cycle < 2.0%

3. $I_{SD} \leq 3A$, $di/dt \leq 100A/\mu s$, $V_{DD} \leq BV_{DSS}$, Starting $T_J = 25^{\circ}C$

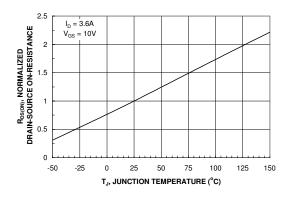
Typical Characteristics



1.6 ORAIN CURRENT (A)

Figure 1. On-Region Characteristics.

Figure 2. On-Resistance Variation with Drain Current and Gate Voltage.



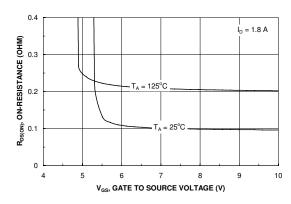
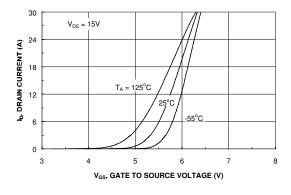


Figure 3. On-Resistance Variation with Temperature.

Figure 4. On-Resistance Variation with Gate-to-Source Voltage.



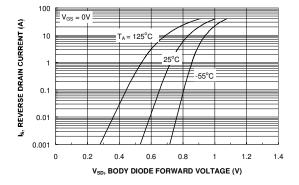
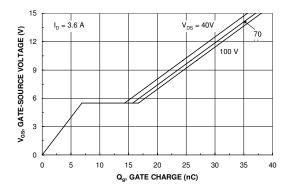


Figure 5. Transfer Characteristics.

Figure 6. Body Diode Forward Voltage Variation with Source Current and Temperature.

Typical Characteristics



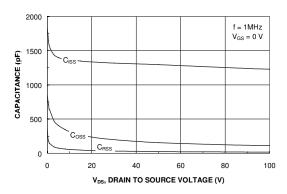


Figure 7. Gate Charge Characteristics.

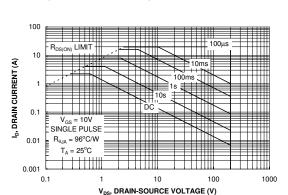


Figure 8. Capacitance Characteristics.

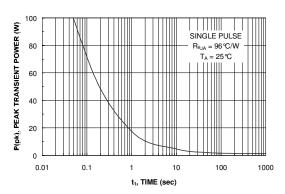


Figure 9. Maximum Safe Operating Area.



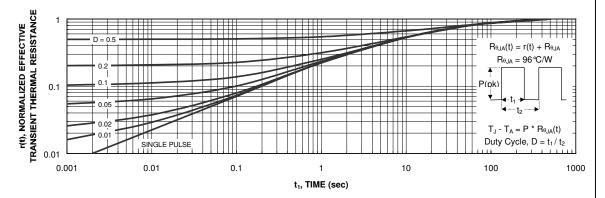


Figure 11. Transient Thermal Response Curve.

Thermal characterization performed using the conditions described in Note 1b. Transient thermal response will change depending on the circuit board design.

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